



SamHop Microelectronics Corp.

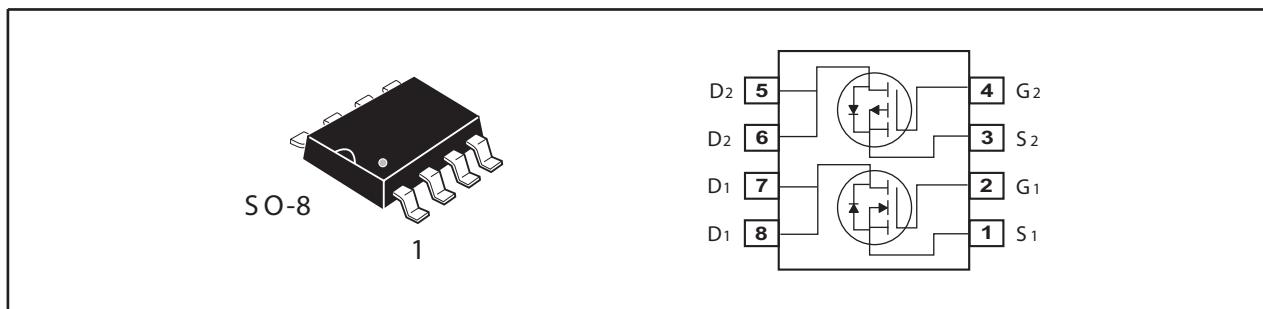
STM8456

Ver 1.0

Dual Enhancement Mode Field Effect Transistor (N and P Channel)

PRODUCT SUMMARY (N-Channel)		
V _{DSS}	I _D	R _{DSON} (mΩ) Max
40V	6.2A	33 @ V _{GS} =10V
		45 @ V _{GS} =4.5V

PRODUCT SUMMARY (P-Channel)		
V _{DSS}	I _D	R _{DSON} (mΩ) Max
-40V	-5.3A	45 @ V _{GS} =-10V
		70 @ V _{GS} =-4.5V



ABSOLUTE MAXIMUM RATINGS (T_A=25°C unless otherwise noted)

Symbol	Parameter	N-Channel	P-Channel	Units
V _{DS}	Drain-Source Voltage	40	-40	V
V _{GS}	Gate-Source Voltage	±20	±20	V
I _D	Drain Current-Continuous ^a	6.2	-5.3	A
	T _A =25°C			
	T _A =70°C	4.9	-4.2	A
I _{DM}	-Pulsed ^b	25	-22	A
E _{AS}	Single Pulse Avalanche Energy ^d	9	16	mJ
P _D	Maximum Power Dissipation ^a	2		W
	T _A =25°C		1.28	
T _J , T _{STG}	Operating Junction and Storage Temperature Range	-55 to 150		°C

THERMAL CHARACTERISTICS

R _{θ JA}	Thermal Resistance, Junction-to-Ambient ^a	62.5	°C/W
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Details are subject to change without notice.

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N-Channel ELECTRICAL CHARACTERISTICS ($T_A=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
OFF CHARACTERISTICS						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	40			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=32V, V_{GS}=0V$			1	μA
I_{GSS}	Gate-Body Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$			± 100	nA
ON CHARACTERISTICS^a						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	1	1.5	3	V
$R_{DS(on)}$	Drain-Source On-State Resistance	$V_{GS}=10V, I_D=6.2A$		26	33	m ohm
		$V_{GS}=4.5V, I_D=5.3A$		33	45	m ohm
g_{FS}	Forward Transconductance	$V_{DS}=10V, I_D=6.2A$		13.8		S
DYNAMIC CHARACTERISTICS^c						
C_{iss}	Input Capacitance	$V_{DS}=20V, V_{GS}=0V$ $f=1.0MHz$		580		pF
C_{oss}	Output Capacitance			82		pF
C_{rss}	Reverse Transfer Capacitance			50		pF
SWITCHING CHARACTERISTICS^c						
$t_{D(on)}$	Turn-On Delay Time	$V_{DD}=20V$ $I_D=1A$ $V_{GS}=10V$ $R_{GEN}=3.3\text{ ohm}$		11		ns
t_r	Rise Time			10.2		ns
$t_{D(off)}$	Turn-Off Delay Time			17.3		ns
t_f	Fall Time			20		ns
Q_g	Total Gate Charge	$V_{DS}=20V, I_D=6.2A, V_{GS}=10V$		11.3		nC
		$V_{DS}=20V, I_D=5.3A, V_{GS}=4.5V$		5.8		nC
Q_{gs}	Gate-Source Charge	$V_{DS}=20V, I_D=6.2A,$ $V_{GS}=10V$		1.2		nC
Q_{gd}	Gate-Drain Charge			2.9		nC
DRAIN-SOURCE DIODE CHARACTERISTICS						
V_{SD}	Diode Forward Voltage ^b	$V_{GS}=0V, I_S=1.3A$		0.79	1.2	V

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P-Channel ELECTRICAL CHARACTERISTICS ($T_A=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
OFF CHARACTERISTICS						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =-250uA	-40			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =-32V , V _{GS} =0V			-1	uA
I _{GSS}	Gate-Body Leakage Current	V _{GS} =±20V , V _{DS} =0V			±100	nA
ON CHARACTERISTICS						
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =-250uA	-1	-1.7	-3	V
R _{DSON}	Drain-Source On-State Resistance	V _{GS} =-10V , I _D =-5.3A		36	45	m ohm
		V _{GS} =-4.5V , I _D =-4.3A		52	70	m ohm
g _{FS}	Forward Transconductance	V _{DS} =-10V , I _D =-5.3A		12		S
DYNAMIC CHARACTERISTICS ^c						
C _{iss}	Input Capacitance	V _{DS} =-20V,V _{GS} =0V f=1.0MHz		980		pF
C _{oss}	Output Capacitance			135		pF
C _{rss}	Reverse Transfer Capacitance			90		pF
SWITCHING CHARACTERISTICS ^c						
t _{D(ON)}	Turn-On Delay Time	V _{DD} =-20V I _D =-1A V _{GS} =-10V R _{GEN} =3.3 ohm		12		ns
t _r	Rise Time			17		ns
t _{D(OFF)}	Turn-Off Delay Time			82		ns
t _f	Fall Time			35		ns
Q _g	Total Gate Charge	V _{DS} =-20V,I _D =-5.3A,V _{GS} =-10V		20.7		nC
		V _{DS} =-20V,I _D =-4.3A,V _{GS} =-4.5V		11		nC
Q _{gs}	Gate-Source Charge	V _{DS} =-20V,I _D =-5.3A, V _{GS} =-10V		1.5		nC
Q _{gd}	Gate-Drain Charge			6.2		nC
DRAIN-SOURCE DIODE CHARACTERISTICS						
V _{SD}	Diode Forward Voltage ^b	V _{GS} =0V,I _S =-1.3A		-0.78	-1.2	V
Notes						
a.Surface Mounted on FR4 Board,t ≤ 10sec. b.Pulse Test:Pulse Width ≤ 300us, Duty Cycle ≤ 2%. c.Guaranteed by design, not subject to production testing. d.Starting T _J =25°C,V _{DD} = 20V,V _{GS} =10V,L=0.5mH.						

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N-Channel

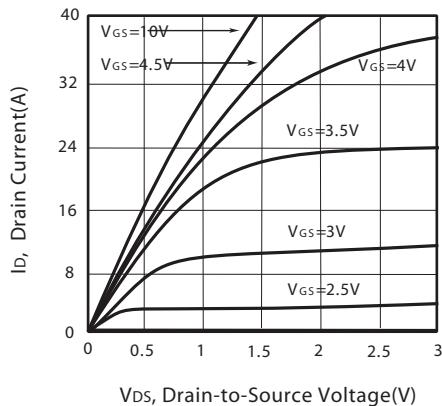


Figure 1. Output Characteristics

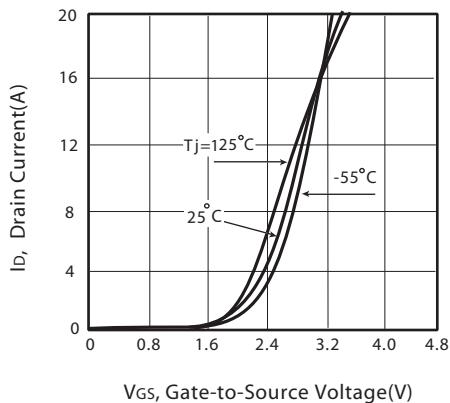


Figure 2. Transfer Characteristics

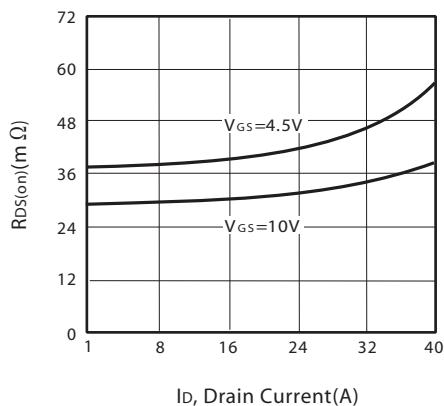


Figure 3. On-Resistance vs. Drain Current and Gate Voltage

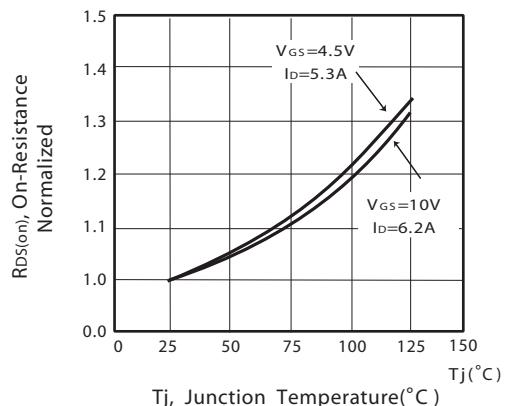


Figure 4. On-Resistance Variation with Drain Current and Temperature

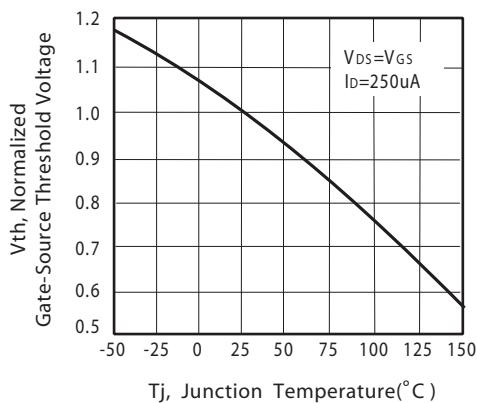


Figure 5. Gate Threshold Variation with Temperature

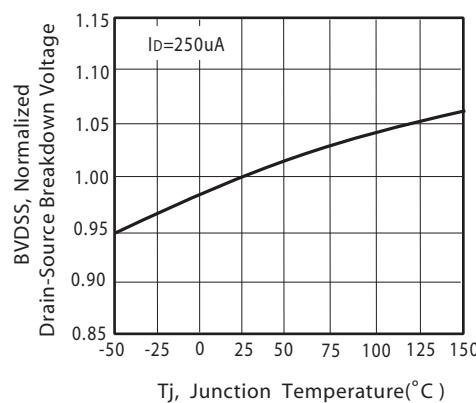
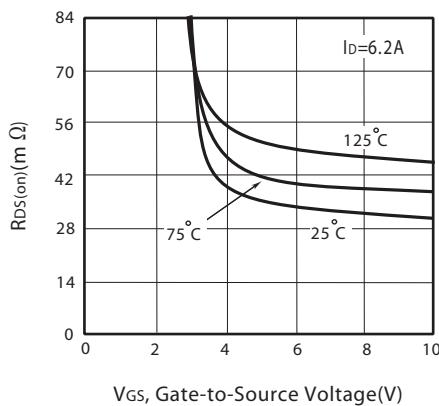


Figure 6. Breakdown Voltage Variation with Temperature

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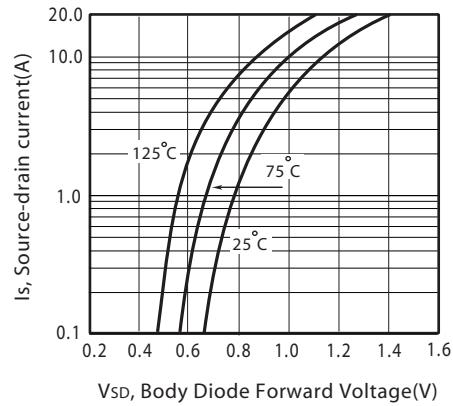
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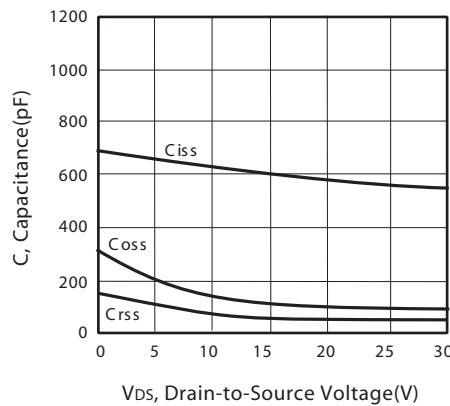
V_{GS}, Gate-to-Source Voltage(V)

Figure 7. On-Resistance vs.
Gate-Source Voltage



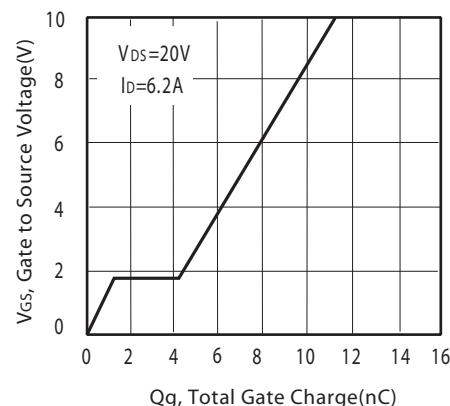
V_{SD}, Body Diode Forward Voltage(V)

Figure 8. Body Diode Forward Voltage
Variation with Source Current



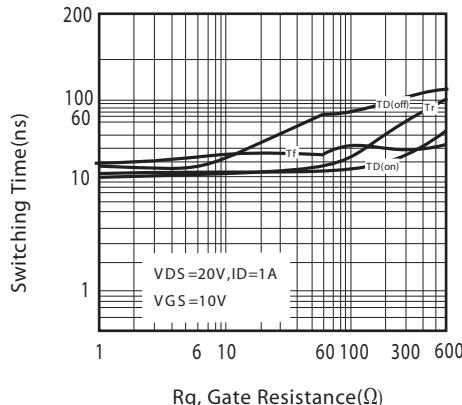
V_{DS}, Drain-to-Source Voltage(V)

Figure 9. Capacitance



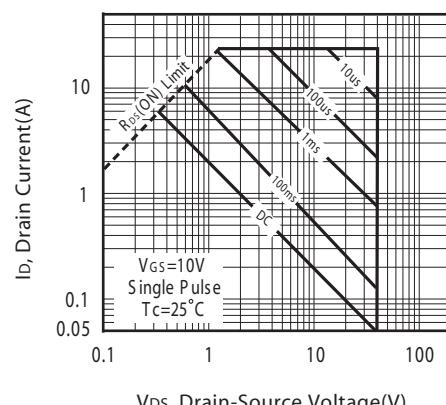
Q_g, Total Gate Charge(nC)

Figure 10. Gate Charge



R_g, Gate Resistance(Ω)

Figure 11. switching characteristics

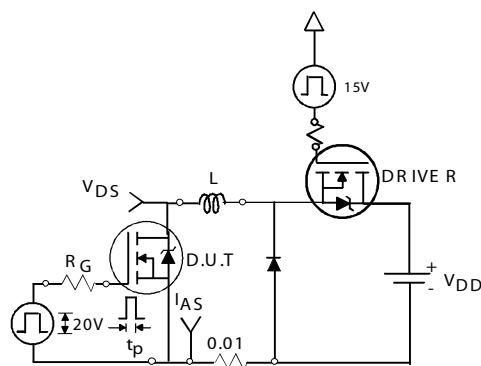


V_{DS}, Drain-Source Voltage(V)

Figure 12. Maximum Safe Operating Area

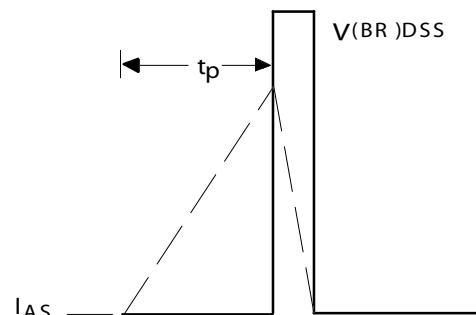
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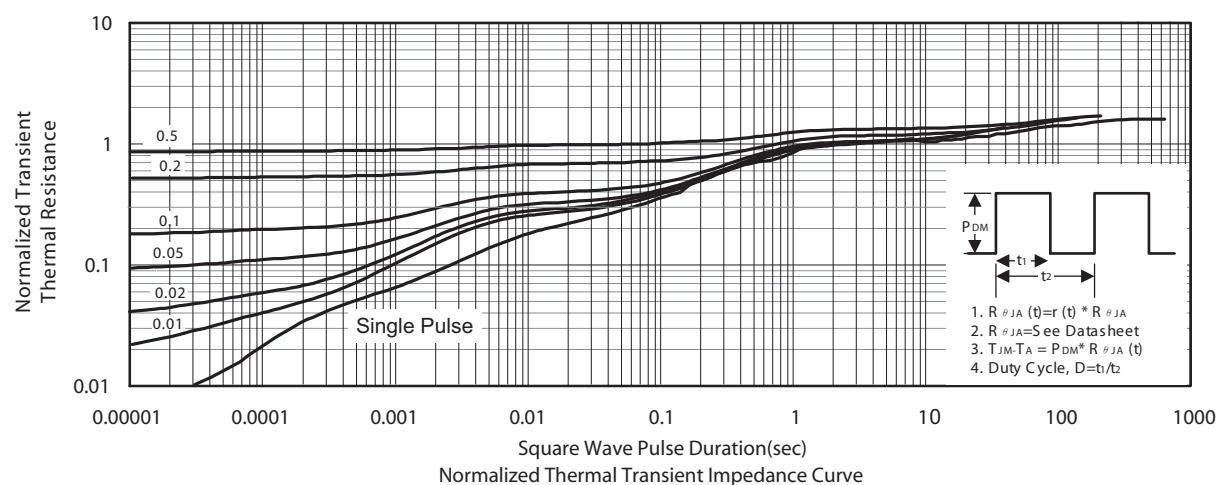
Unclamped Inductive Test Circuit

Figure 13a.



Unclamped Inductive Waveforms

Figure 13b.



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P-Channel

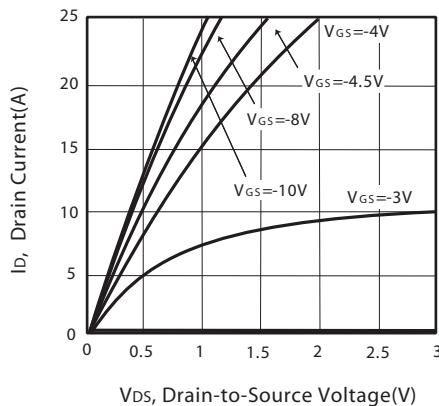


Figure 1. Output Characteristics

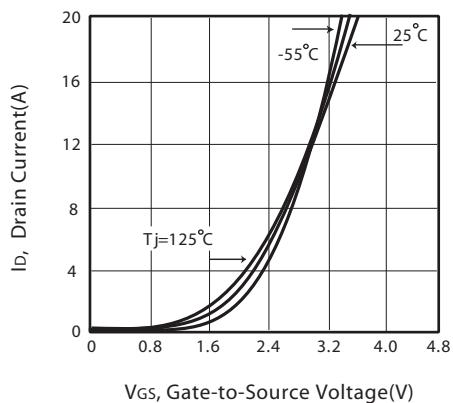


Figure 2. Transfer Characteristics

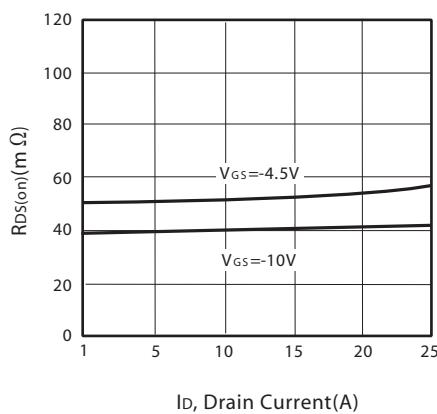


Figure 3. On-Resistance vs. Drain Current and Gate Voltage

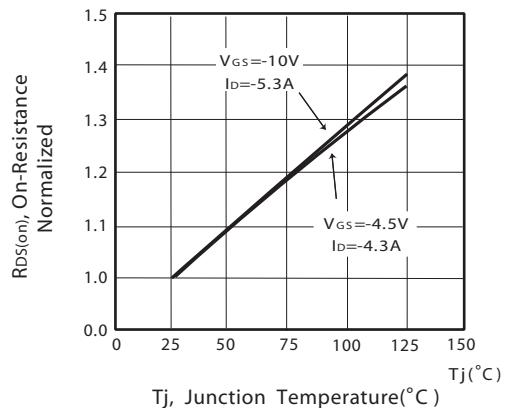


Figure 4. On-Resistance Variation with Drain Current and Temperature

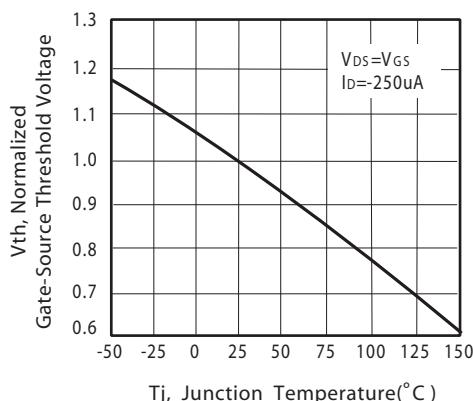


Figure 5. Gate Threshold Variation with Temperature

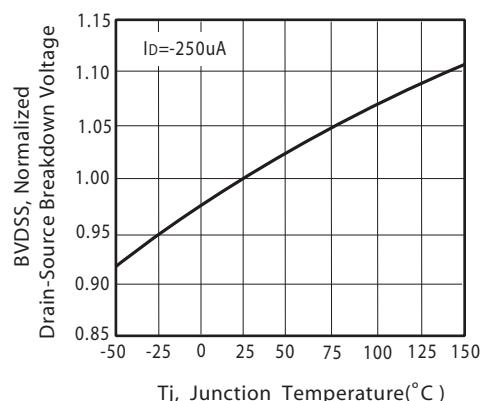


Figure 6. Breakdown Voltage Variation with Temperature

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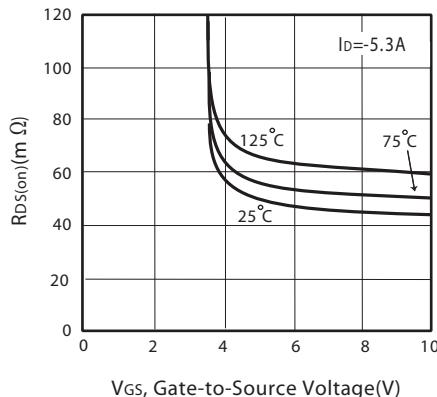


Figure 7. On-Resistance vs.
Gate-Source Voltage

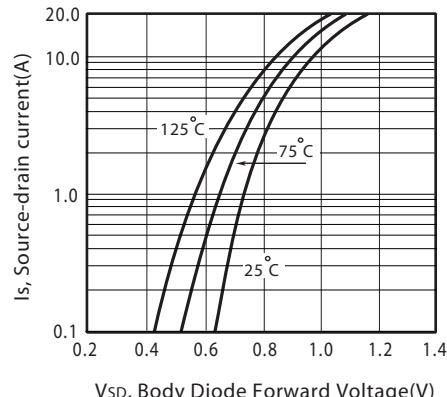


Figure 8. Body Diode Forward Voltage
Variation with Source Current

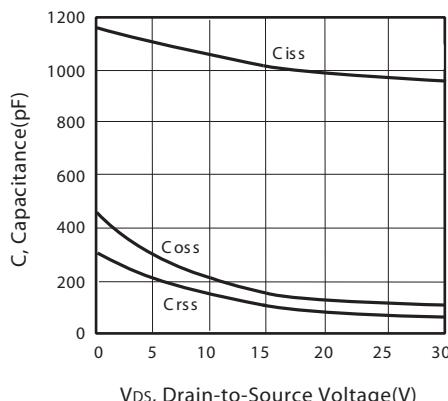


Figure 9. Capacitance

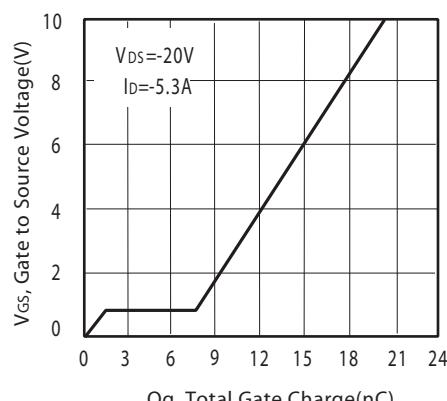


Figure 10. Gate Charge

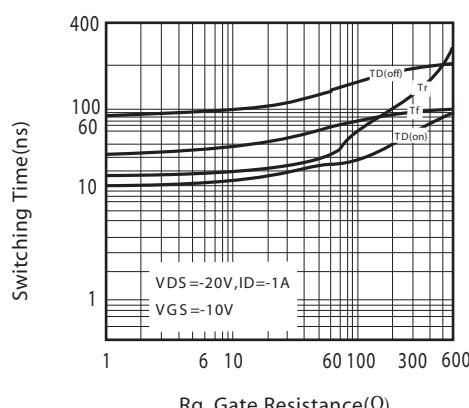


Figure 11. switching characteristics

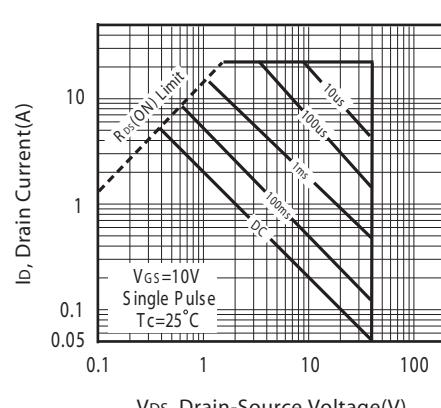
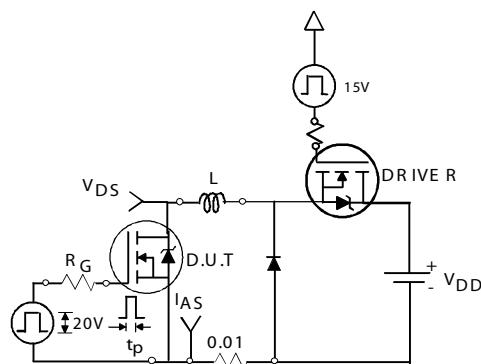


Figure 12. Maximum Safe Operating Area

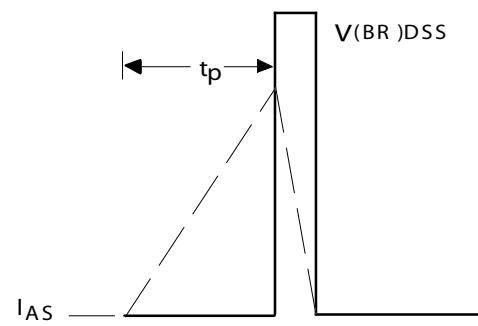
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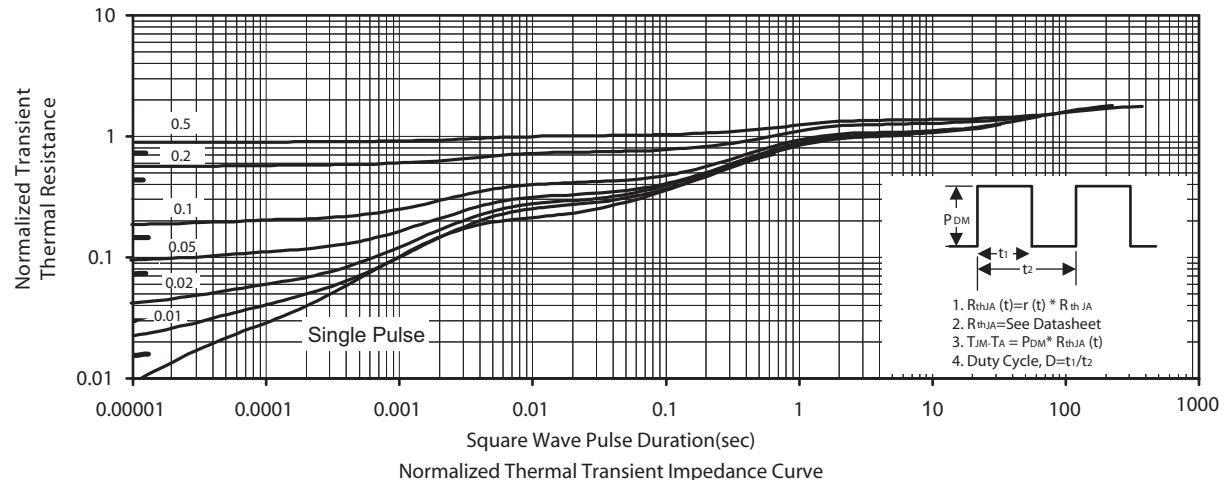
Unclamped Inductive Test Circuit

Figure 13a.



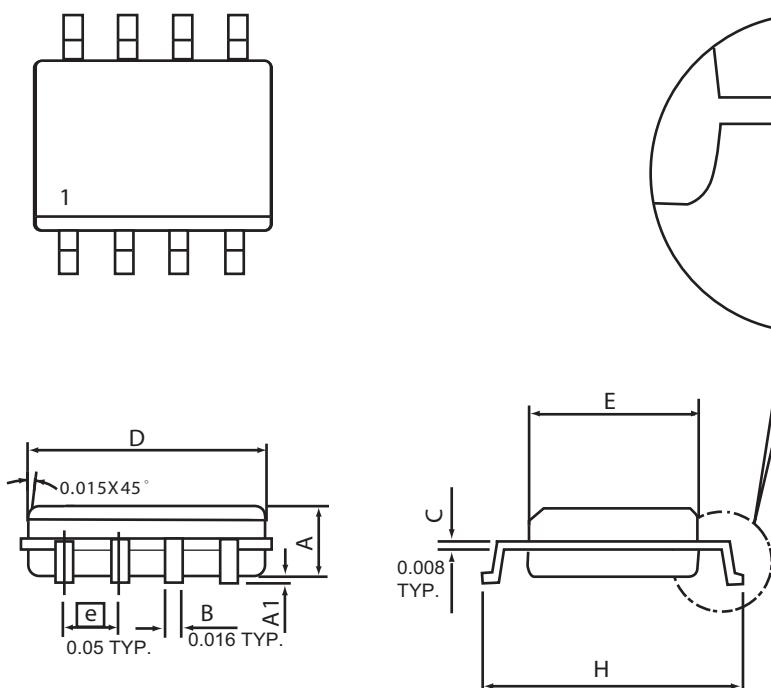
Unclamped Inductive Waveforms

Figure 13b.



PACKAGE OUTLINE DIMENSIONS

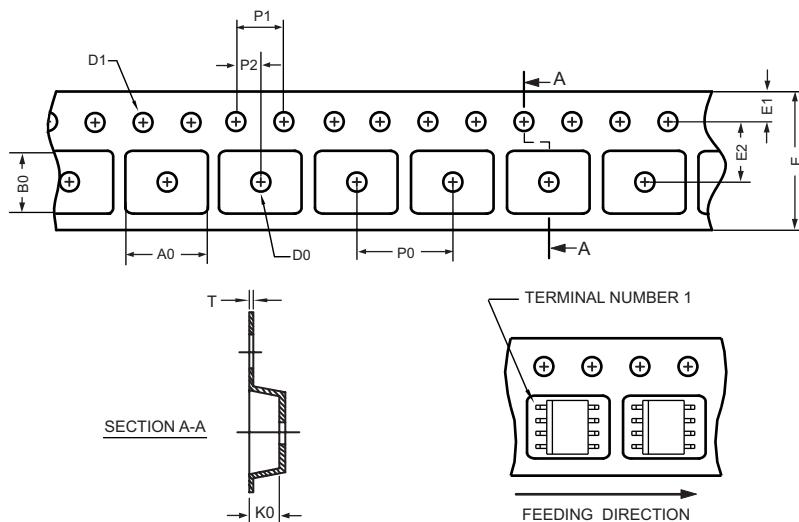
SO-8



SYMBOLS	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	1.35	1.75	0.053	0.069
A1	0.10	0.25	0.004	0.010
D	4.80	4.98	0.189	0.196
E	3.81	3.99	0.150	0.157
H	5.79	6.20	0.228	0.244
L	0.41	1.27	0.016	0.050
θ	0°	8°	0°	8°

SO-8 Tape and Reel Data

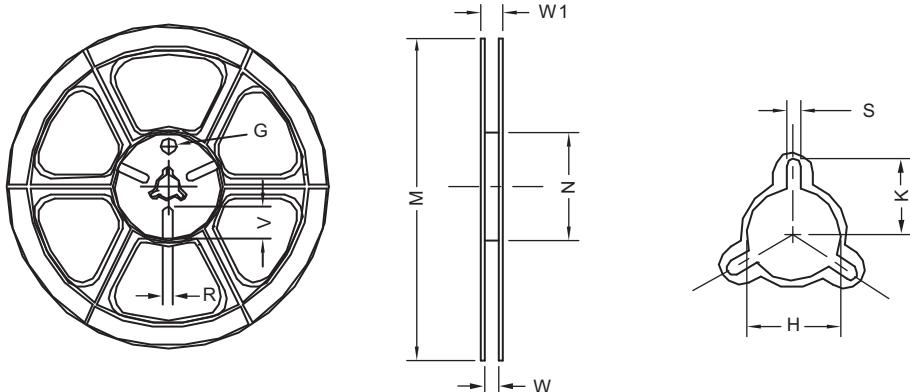
SO-8 Carrier Tape



unit:mm

PACKAGE	A0	B0	K0	D0	D1	E	E1	E2	P0	P1	P2	T
SOP 8N 150[mil]	6.50 ± 0.15	5.25 ± 0.10	2.10 ± 0.10	$\phi 1.5$ (MIN)	$\phi 1.55$ ± 0.10	12.0 $+0.3$ -0.1	1.75 ± 0.10	5.5 ± 0.10	8.0 ± 0.10	4.0 ± 0.10	2.0 ± 0.10	0.30 ± 0.013

SO-8 Reel



UNIT:mm

TAPE SIZE	REEL SIZE	M	N	W	W1	H	K	S	G	R	V
12 mm	$\phi 330$	330 ± 1	62 ± 1.5	12.4 $+0.2$	16.8 -0.4	$\phi 12.75$ $+0.15$	---	2.0 ± 0.15	---	---	---